

Supporting Information

Measurement of Optical Properties in Organic Photovoltaic Materials Using Monochromated Electron Energy-Loss Spectroscopy

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Figure S1 shows the collected variable angle spectroscopy ellipsometry (VASE) Ψ and Δ data for thin films of CuPc (a and b), C₆₀ (c and d), PCBM (e and f), and P3HT (g and h) for different angles of incidence (blue - 60°, green - 65°, and yellow - 70°). The fitted models are shown in the red lines, and all fit fairly well with the collected Ψ and Δ data.

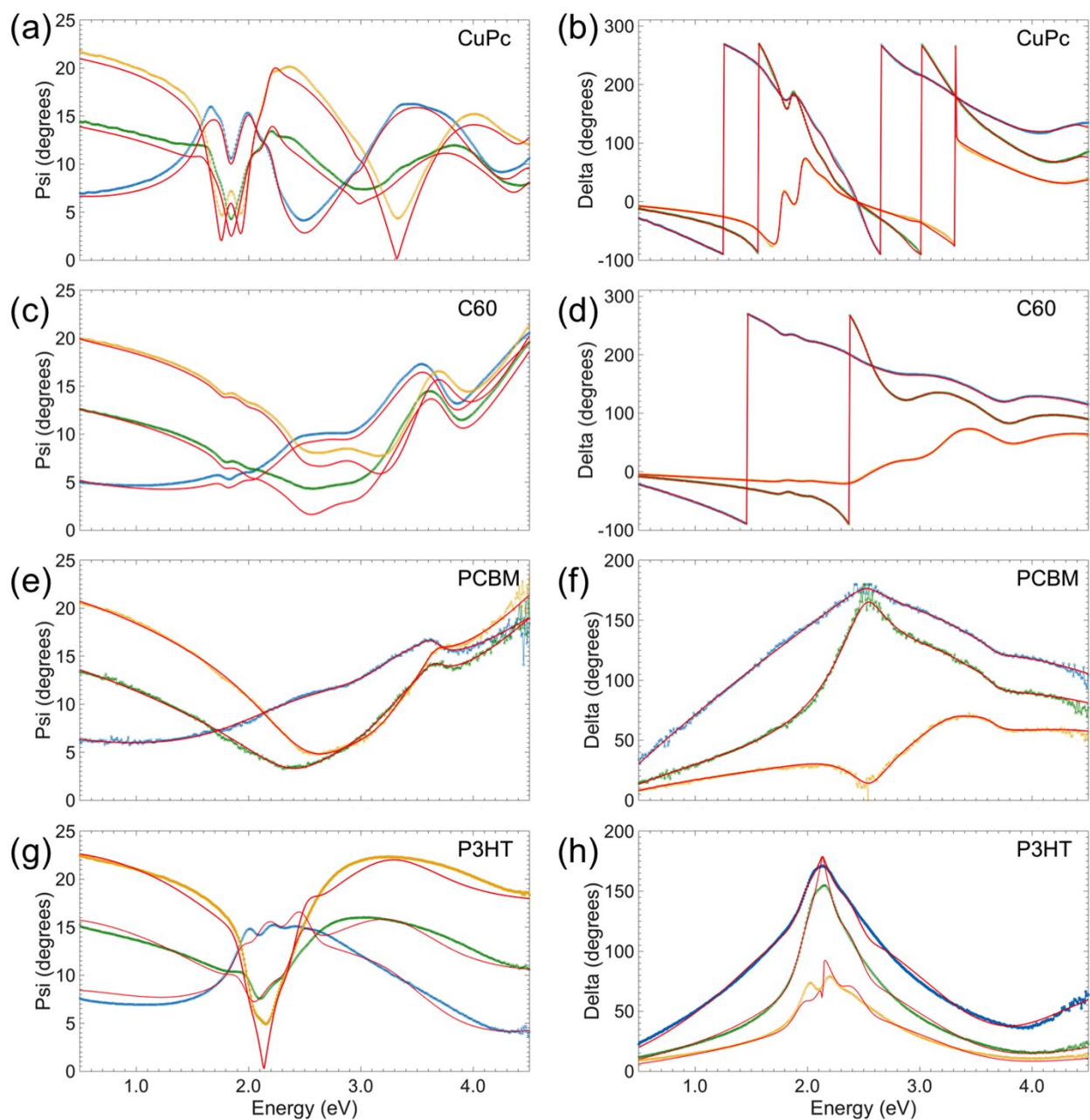


Figure S1. Collected VASE data for CuPc, C₆₀, PCBM, and P3HT with the fitted models.